



AP3 & AP4

QUALIFICATION REPORT

I. INTRODUCTION

The AP3 and AP4 are high dynamic range FETs packaged in a high frequency surface mount package. The combination of low noise figure and high output IP3 at the same bias point makes them ideal for receiver and transmitter applications.

II. SCOPE

This report summarizes the reliability qualification of the AP3 and AP4 high dynamic range amplifiers manufactured at the WJ Communications facility in Milpitas, CA and assembled in a 3 x 3 Land Grid Array package. The process used is our standard H11, 4-inch process. The reliability data are obtained through the performance of specified accelerated stress tests described in this document.

III. APPLICABLE DOCUMENTS

All the test procedures and test methods are consistent with industry standards. The standards referenced in this document are JEDEC standard 22 and MIL STD 883.

IV. QUALIFICATION TEST PLAN

The AP3 and AP4 are processed using the same process flow and are packaged in the 3x3 LGA package, therefore qualification testing done on one part qualifies the entire family of parts.

Stress or Test	Device Hours/ Cycles	Sample Size	Failed Units	Date	Reference Document	Part Tested
High Temp Op Life	96,000	96	1	1999	JESD22 A108	AP4
Temperature Cycle	100,000	100	0	1999	JESD22 A104	AP4
Unbiased Autoclave	9,600	100	0	1999	JESD22 A102	AP4
Physical Dimensions		15	0	2000	JESD22 A108	AP4
Solderability		25	0	2000	MS883 M2003	AP4
Res. To Solvents		3	0	2000	JESD22 A108	AP4
Resistance to soldering heat		25	0	2000	JESD22 B106	AP4
Gross & Fine Leak		100	0	2000	MS883 M1014	AP4

V. DISCUSSION OF RESULTS

1. HIGH TEMPERATURE OPERATING LIFE

96 AP4 parts were tested for High Temperature Operating Life with one failure.

VI. CONCLUSIONS

The Reliability Qualification Data demonstrates that the AP3 and AP4 amplifiers fabricated at the WJ Communications Milpitas facility and assembled in a 3x3 LGA package demonstrates high reliability and quality levels.